511.40998X00

AUG 2 5 2004 3

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s):

N. KOYAMA et al

Serial No.:

10/018,188

Filed:

December 18, 2001

For:

CMP ABRASIVE, METHOD FOR POLISHING SUBSTRATE AND METHOD FOR MANUFACTURING SEMICONDUCTOR

DEVICE USING THE SAME, AND ADDITIVE FOR CMP

ABRASIVE

Group:

3724

Examiner:

T. ELEY

RECEIVED

ALIG 3 0 2004

TECHNOLOGY CENTER 3700

<u>AMENDMENT</u>

MS: AMENDMENTS
Commissioner For Patents
POB 1450

Alexandria, VA 22313-1450

August 25, 2004

Sir:

In response to the Office Action dated February 25, 2004, the period of response for which extension of time is requested in the attached Petition for Extension of Time, please amend the above-identified application as listed below and as set forth on the following pages:

Amendments to the Specification;

Amendments to the Claims; and

Remarks are included following the Amendments.

08/26/2004 EABUBAK1 00000061 10018188

01 FC:1202

36.00 OP